Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/661,638	HIRAIWA ET AL.	
Examiner	Art Unit	
Lois Zheng	1793	

SEARCHED					
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
	<u> </u>				

(INCLUDING SEAF	(INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR			
Inventorship search	1/11/2008	LLZ			
Updated EAST search	1/11/2008	LLZ			
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